Search Notes

Application/Control	No.

Applicant(s)/Patent under Reexamination

10/549,615

Linh V. Nguyen

Examiner

HOSHINO ET AL.

2819

SEARCHED				
Class	Subclass	Date	Examiner	
375	340,341 335,265 207,267	6/21/2006	LN	
370	252,335	6/21/2006	LN	
370	270,331	6/21/2006	LN	
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH I (INCLUDING SEAR	NOTES CH STRATEGY	")
	DATE	EXMR
East searched-see printout	6/21/2006	LN